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ENGLISH LANGUAGE TRANSLATION OF THE  
AMENDMENTS TO THE CLAIMS UNDER PCT  
ARTICLE 19 (35 U.S.C. 371 (C)(3)).

card that inspects an electrical characteristic of an object to be inspected, including: a contactor; a circuit board; an intermediate member provided between the contactor and the circuit board to have the contactor and the circuit board in elastic and electrical contact with each other; a coupling member integrating the contactor, the circuit board, and the intermediate member; and a reinforcing member reinforcing the circuit board integrated via the coupling member.

[0009]

The intermediate member may be an interposer having a substrate and a plurality of elastically deformable contacts provided at least on the circuit board side of the substrate, the contacts not being fixed to the circuit board.

[0010]

In the probe card, a plurality of elastically deformable contacts may be provided as the intermediate member on the contactor, the contacts not being fixed to the circuit board.

[0011]

The intermediate member may be made of conductive rubber.

[0012]

In the probe card, elastic members may be interposed between the contactor and the circuit board and between the circuit board and the reinforcing member respectively.

[0013]

In the probe card, the contactor may have a ceramic substrate and a plurality of probes provided on a surface of the ceramic substrate on a side to be in contact with the object to be inspected.

[0014]

The reinforcing member may have a flat plate shape and be disposed opposite the intermediate member across the circuit board, the reinforcing member and the contactor may be fixed to each other via the coupling member, and the circuit board may be movably attached to the coupling member.

[0015]

Further, the reinforcing member may have a pressing member pressing the circuit board toward the contactor side.

[0016]

10       The reinforcing member may have a plurality of the pressing members.

[Effect of the Invention]

[0017]

15       According to the present invention, it is possible to provide a probe card realizing sure electrical connection between the contactor and an object to be inspected without influenced by heat and a reduction in the pre-heating time, leading to an enhanced throughput.

[Brief Description of the Drawings]

[0018]

20       [FIGs. 1]

Views schematically showing an embodiment of a probe card of the present invention, (a) being a cross-sectional view thereof and (b) being an enlarged cross-sectional view of an interposer.

[Name of Document] What Is Claimed Is

[Claim 1] A probe card that inspects an electrical characteristic of an object to be inspected, comprising: a contactor; a circuit board; an intermediate member provided between said contactor and said circuit board  
5 to have said contactor and said circuit board in elastic and electrical contact with each other; a coupling member integrating said contactor, said circuit board, and said intermediate member; and a reinforcing member reinforcing said circuit board integrated via said coupling member.

[Claim 2](amended) The probe card according to claim 1,  
10 wherein said intermediate member is an interposer having a substrate and a plurality of elastically deformable contacts provided at least on said circuit board side of the substrate, the contacts not being fixed to said circuit board.

[Claim 3](amended) The probe card according to claim 1,  
15 wherein a plurality of elastically deformable contacts are provided as said intermediate member on said contactor, the contacts not being fixed to said circuit board.

[Claim 4] The probe card according to claim 1,  
wherein said intermediate member is made of conductive rubber.

20 [Claim 5] The probe card according to claim 1,  
wherein elastic members are interposed between said contactor and said circuit board and between said circuit board and said reinforcing member respectively

[Claim 6] The probe card according to claim 1,  
25 wherein said contactor has a ceramic substrate and a plurality of probes provided on a surface of the ceramic substrate on a side to be in

contact with the object to be inspected.

[Claim 7] The probe card according to claim 1,

wherein said reinforcing member has a flat plate shape and is disposed opposite the intermediate member across the circuit board,

5 wherein said reinforcing member and said contactor are fixed to each other via said coupling member, and

wherein said circuit board is movably attached to said coupling member.

[Claim 8] The probe card according to claim 7,

10 wherein said reinforcing member has a pressing member pressing said circuit board toward said contactor side.

[Claim 9] The probe card according to claim 8,

wherein said reinforcing member has a plurality of the pressing members.

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